

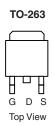
# CEB14P20-VB Datasheet P-Channel 200 V (D-S) MOSFET

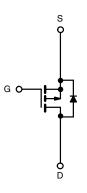
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	-200			
R <sub>DS(on)</sub> (Ω)	$V_{GS} = -10 \text{ V}$	0.50		
Q <sub>g</sub> max. (nC)	44			
Q <sub>gs</sub> (nC)	7.1			
Q <sub>gd</sub> (nC)	27			
Configuration	Single			

#### **FEATURES**

- Dynamic dV/dt rating
- · Repetitive avalanche rated
- P-channel
- · Fast switching
- Ease of paralleling
- Simple drive requirements







P-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			LIMIT	UNIT		
Drain-Source Voltage			-200	V		
Gate-Source Voltage			± 20	V		
V <sub>GS</sub> at -10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	-11	A		
	T <sub>C</sub> = 100 °C		-6.8			
Pulsed Drain Current <sup>a</sup>			-44			
Linear Derating Factor			1.0	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>			700	mJ		
Repetitive Avalanche Current a			-11	Α		
Repetitive Avalanche Energy <sup>a</sup>		E <sub>AR</sub>	13	mJ		
T <sub>C</sub> = 25 °C		$P_{D}$	125	W		
Peak Diode Recovery dV/dt <sup>c</sup>		dV/dt	-5.0	V/ns		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
	V <sub>GS</sub> at -10 V	$V_{GS} \text{ at -10 V} \qquad \frac{T_C = 25 \text{ °C}}{T_C = 100 \text{ °C}}$ $T_C = 25 \text{ °C}$	$\begin{tabular}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		

for 10 s

6-32 or M3 screw

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}=$  -50 V, starting  $T_J=25$  °C, L = 8.7 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=$  -11 A (see fig. 12). c.  $I_{SD}\leq$  -11 A, dl/dt  $\leq$  150 A/µs,  $V_{DD}\leq$   $V_{DS}$ ,  $V_{DS}$ 0 °C.

Soldering Recommendations (Peak temperature) d

d. 1.6 mm from case.

Mounting Torque

°C

lbf · in

 $N\cdot m$ 

300 10

1.1



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62			
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	1.0			

PARAMETER	SYMBOL	TES	TEST CONDITIONS			MAX.	UNIT
Static				Į.	!	!	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		-200	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I <sub>D</sub> = -1 mA		-0.2	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	· V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-2.0	-	-4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	,	V <sub>GS</sub> = ± 20 V		-	± 100	nA
7 Oals Walless Buds O and		$V_{DS} = -200 \text{ V}, V_{GS} = 0 \text{ V}$		-	-	-100	μА
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -160 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	-	-500	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = -10 V	I <sub>D</sub> = -6.6 A <sup>b</sup>	-	0.50	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	-50 V, I <sub>D</sub> = -6.6 A <sup>b</sup>	4.1	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = -25 \text{ V},$		-	1200	-	pF
Output Capacitance	C <sub>oss</sub>			-	370	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.	.0 MHz, see fig. 5	-	81	-	1
Total Gate Charge	Qg		I <sub>D</sub> = -11 A, V <sub>DS</sub> = -160 V, see fig. 6 and 13 <sup>b</sup>	-	=.	44	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = -10 V		-	-	7.1	
Gate-Drain Charge	$Q_{gd}$			-	=.	27	
Turn-On Delay Time	t <sub>d(on)</sub>			-	14	-	
Rise Time	t <sub>r</sub>	$V_{DD}$ = -100 V, $I_{D}$ = -11 A $R_{g}$ = 9.1 $\Omega$ , $R_{D}$ = 8.6 $\Omega$ , see fig. 10 b		-	43	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	39	-	
Fall Time	t <sub>f</sub>			-	38	-	
Internal Drain Inductance	$L_{D}$	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	- nH
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	
Gate Input Resistance	$R_g$	f = 1 MHz, open drain		0.3	-	1.7	Ω
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym showing the	MOSFET symbol showing the		-	-11	^
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p -n junction diode		-	-	-44	A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C	$T_J = 25$ °C, $I_S = -11$ A, $V_{GS} = 0$ V b		-	-5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = -11 A, dI/dt = 100 A/μs b		-	250	300	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	2.9	3.6	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					L <sub>D</sub> )

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300  $\mu s$ ; duty cycle  $\leq$  2 %.



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

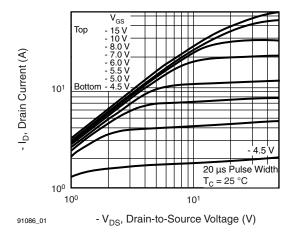


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

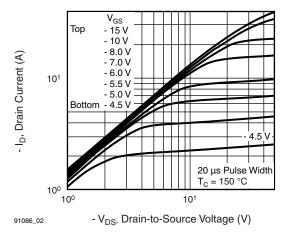


Fig. 2 - Typical Output Characteristics, T<sub>C</sub> = 150 °C

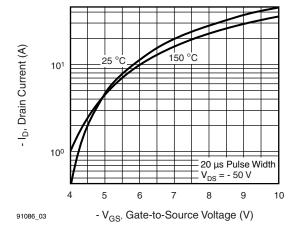


Fig. 3 - Typical Transfer Characteristics

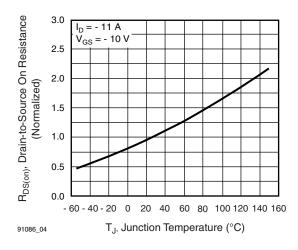


Fig. 4 - Normalized On-Resistance vs. Temperature

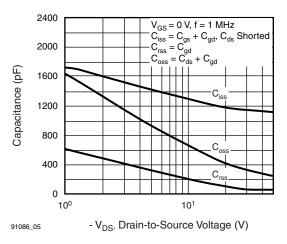


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

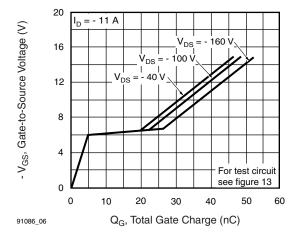


Fig. 6 - Typical Gate Charge vs. Drain-to-Source Voltage



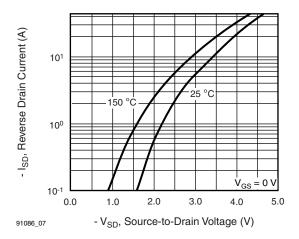


Fig. 7 - Typical Source-Drain Diode Forward Voltage

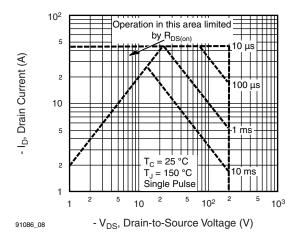


Fig. 8 - Maximum Safe Operating Area

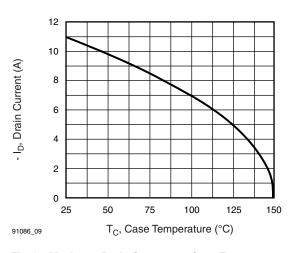


Fig. 9 - Maximum Drain Current vs. Case Temperature

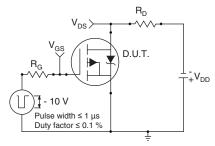


Fig. 10a - Switching Time Test Circuit

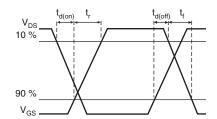


Fig. 10b - Switching Time Waveforms

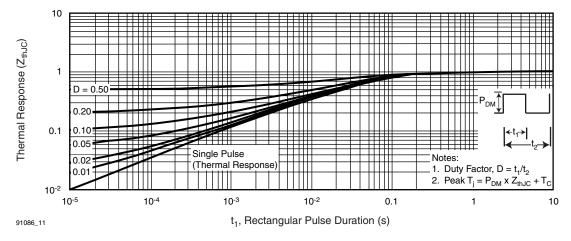


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



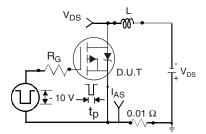


Fig. 12a - Unclamped Inductive Test Circuit

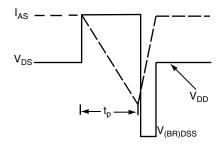


Fig. 12b - Unclamped Inductive Waveforms

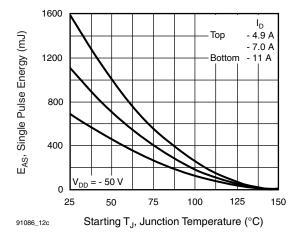


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

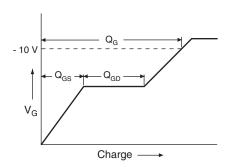


Fig. 13a - Basic Gate Charge Waveform

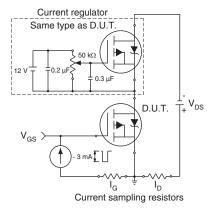
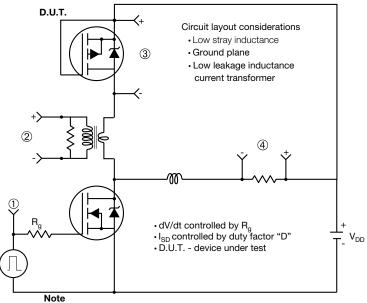


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver

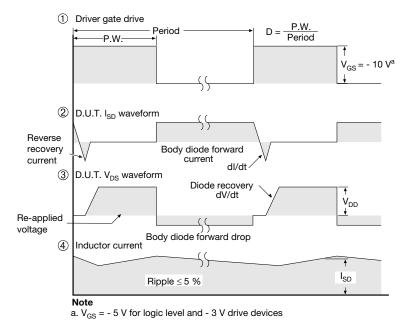
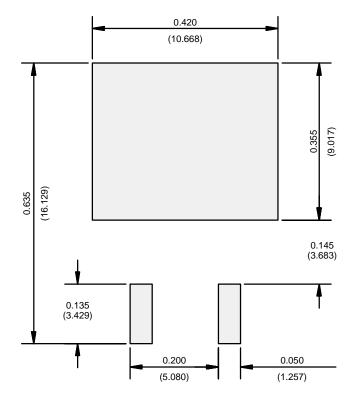


Fig. 14 - For P-Channel



### RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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